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PATENT

E UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

TOKUDA et al.

Atty. Dkt. No.: P67090US0

Serial No.: 10/072,973

Group Art Unit: 2122

Filed: February 12, 2002

For: SYSTEM AND METHOD FOR ACCURATE GRAMMAR ANALYSIS USING A PART-

OF-SPEECH TAGGED (POST) PARSER AND LEARNERS' MODEL

INFORMATION DISCLOSURE STATEMENT

BOX DD Commissioner of Patents Washington, DC 20231 RECEIVED

JUL 0 3 2002

Sir:

Technology Center 2100

As a means of complying with the duty of disclosure under 37 CFR §1.56, and in accordance with 37 CFR §\$1.97 and 1.98, Applicant(s), through the undersigned attorney, submits this Information Disclosure Statement. The patents, publications or other information submitted herewith are listed on the attached Form PTO-1449 and copies are attached.

In accordance with 37 CFR §1.97(b)(3), this Information Disclosure Statement is being filed before the mailing date of a first Office Action on the merits of the above-identified application.

Respectfully submitted,

JACOBSON HOLMAN PLLC

Ву

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Date: July 1, 2002

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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT

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^{*} EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).